	Searcn Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/033,031	INOUE, RUMIKO	
Examiner	Art Unit	
Michael Chuen	2661	

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	352-356, 401	9/21/2005	MPC
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SEARCH	STRATEGY	)
	DATE	EXMR
370/352-356, 401 (text search only - see search history printout)	9/21/2005	MPC
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